

Search Notes



Application/Control No.

10/621,451

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	185.29	1/15/2005	HN
	185.11		
	185.09		
	185.12		
update search as above		6/24/05	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
365	185.29	6/24/05	HN
	185.11		
	185.12		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	1/15/2005	HN
(update)	6/24/05	HN